

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977/226002/US3548D1	Application No. 09/596,755
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hisashi Ohtani	
		Filing Date June 15, 2000	Group Art Unit 1765

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,523,262	6/4/96	Fair, et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes
	AL						
	AM						
	AN						
	AO						
	AP						

**Other Documents (include Author, Title, Date, and Place of Publication)**

Examiner Initial	Desig. ID	Document
	AQ	Hirano, et al., "Low Temperature Activation method of Poly-Si films using Rapid Thermal Annealing", Vol. 3014, pgs. 119-126, Proceedings, February 1997.
	AR	
	AS	
	AT	

Examiner's signature

EXAMINER Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with communication to applicant.

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**U.S. Patent Documents**

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
AA	AA	5,771,110	6/23/98	Hirano, et al.			
AB	AB	5,837,568	11/17/98	Yoneda, et al.			
AC							
AD							
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AF							
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